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| Sales price [Euro] | Unit | Description | Accre- dited | ltem No. |
|-----------------------|------|---|--------------------|--------------|
| | | resistance calibration | oltage (DC) and re | Electical vo |
| 2.438,00 | Pcs | Calibration of a voltage reference standard (Zener) | YES | K02.001 |
| | Pcs | Electrical measurement/calibration, secondary, acc. to quotation | Contact DFM | K02.099 |
| | Pcs | Electrical measurement/calibration according to quotation | Contact DFM | K02.999 |
| | | | try | Thermomet |
| 67,00 | Pcs | Thermometric calibration, contact, one temp. point | YES | K02.101 |
| 13,00 | Pcs | Thermometric calibration, contact, further thermometer, same temp. | YES | K02.102 |
| 134,00 | Pcs | Thermometric calibration, contact, certificate | | K02.103 |
| 27,00 | Pcs | Thermometric calibration, contact, further certificate | | K02.104 |
| | Pcs | Thermometric calibration, contact, acc. to quotation | Contact DFM | K02.199 |
| 67,00 | Pcs | Thermometric calibration, contactless (IR), one temp. point | YES | K02.201 |
| 13,00 | Pcs | Thermometric calibration, contactless (IR), further thermometer, same temp. | YES | K02.202 |
| 134,00 | Pcs | Thermometric calibration, contactless (IR), certificate | | K02.203 |
| 27,00 | Pcs | Thermometric calibration, contactless (IR), further certificate | | K02.203 |
| | Pcs | Thermometric calibration, contactless (IR), acc. to quotation | Contact DFM | K02.299 |
| | | | | Pressure |
| 67,00 | Pcs | Pressure calibration, one pressure point | YES | K02.301 |
| 13,00 | Pcs | Pressure calibration, further pressure instrument, same point | YES | K02.302 |
| 134,00 | Pcs | Pressure calibration, certificate | | K02.303 |
| 27,00 | Pcs | Pressure calibration, further certificate | | K02.304 |
| | Pcs | Pressure calibration, acc. to quotation | Contact DFM | K02.399 |

Calibration of Electrolytic Conductivity

| K03.001 | YES | Characterisation of solution at 24°C-26°C | Pcs | 746,00 |
|---------|-------------|---|-----|--------|
| K03.002 | YES | Subsequent measurement of same solution at 24°C-26°C | Pcs | 508,00 |
| K03.003 | NO | Characterisation of solution at 24°C-26°C without certificate | Pcs | 629,00 |
| K03.004 | YES | Characterisation of solution 15°C-35°C | Pcs | 941,00 |
| K03.005 | NO | Characterisation of solution 10°C-60°C | Pcs | 967,00 |
| K03.006 | YES | Subsequent measurement of same solution at 15°C-35°C | Pcs | 632,00 |
| K03.099 | Contact DFM | Characterisation of solution according to quotation | Pcs | |

Calibration of conductivity cell constant and conductivity

| K03.101 | YES | Calibration of conductivity sensor cell constant or conductivity measurement system, per measurement point, \geq 3 points | Pcs | 425,00 |
|---------|-------------|---|-----|--------|
| K03.102 | YES | Calibration of conductivity sensor cell constant or conductivity measurement system in CRM fluids at 10 mS/m, 100 mS/m, 1 S/m or 10 S/m, per point and per CRM, incl. CRM | Pcs | 903,00 |
| K03.199 | Contact DFM | Calibration of conductivity sensor cell constant or conductivity measurement system according to quotation | Pcs | |

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| Item No. | Accre- dited | Description | Unit | Sales price [Euro] |
|-------------|------------------|--|------|-----------------------|
| Calibration | of reference ele | ctrode | | |
| K03.201 | YES | Determination of electrochemical reference electrode potential | Pcs | 964,00 |
| Calibration | of pH | | | |
| K03.301 | Contact DFM | Secondary pH calibration, according to quotation | Pcs | |
| Interferome | tric gauge block | calibration length calibration | | |
| K04.001 | YES | Gauge block calibration, first gauge block (1 block) | Pcs | 287,00 |
| K04.002 | YES | Gauge block calibration, following 8 blocks (2-9) in the same set, per block | Pcs | 82,00 |
| K04.003 | YES | Gauge block calibration, each following gauge block (10 -) in the same set | Pcs | 43,00 |
| K04.004 | YES | Gauge block calibration, M10 standard set | Pcs | 986,00 |
| K04.005 | YES | Gauge block calibration, M122 standard set | Pcs | 5.792,00 |
| K04.999 | Contact DFM | Gauge block calibration according to quotation | Pcs | |

Optical radiometry calibration

| K05.001 | YES | Detector / power meter calibration at one power level and wavelength, visible light | Pcs | 779,00 |
|---------|-------------|---|-------|---------|
| K05.002 | YES | Detector / power meter calibration per subsequent power level or wavelength, visible light | Pcs | 486,00 |
| K05.020 | YES | Power meter / detector calibration at one power level and wavelength, NIR, 0.7 $\%$ | Pcs | 623,00 |
| K05.021 | YES | Power meter / detector calibration per following power level or wavelength, NIR, 0.7 $\%$ | Pcs | 389,00 |
| K05.022 | YES | Power meter or detector calibration at one power level and wavelength, NIR, 1.5 $\%$ | Pcs | 389,00 |
| K05.023 | YES | Power meter or detector calibration, per subsequent power level or wavelength, NIR, 1.5 $\%$ | Pcs | 262,00 |
| K05.024 | YES | High-power detector / power meter calibration at one power level and wavelength, NIR | Pcs | 658,00 |
| K05.040 | Contact DFM | Spectral calibration of power meter / detector at 800 - 1650 nm, prices from | Pcs 1 | .460,00 |
| K05.041 | YES | Linearity of detector / power meter, -40 dBm to -5 dBm | Pcs | 583,00 |
| K05.042 | YES | Linearity of detector / power meter, -60 dBm to -40 dBm | Pcs | 117,00 |
| K05.043 | YES | Linearity of detector / power meter, -5 dBm to +10 dBm | Pcs | 117,00 |
| K05.044 | YES | Linearity of detector / power meter, -5 dBm to +23 dBm | Pcs | 195,00 |
| K05.060 | YES | Calibration of fibre optical attenuator, one wavelength | Pcs | 437,00 |
| K05.070 | NO | Homogenity of detectors | Pcs | 546,00 |
| K05.071 | NO | Calibration of laser beam profilers | Pcs | 750,00 |
| K05.072 | NO | Laser classification, per wave length | Pcs | 605,00 |
| K05.080 | YES | Calibration of optical spectrum analyzer or laser wavelength, one range | Pcs | 579,00 |
| K05.081 | YES | Calibration of optical spectrum analyzer or laser wavelength, two ranges | Pcs | 739,00 |
| K05.082 | YES | Calibration of wavelength meter / laser wavelength | Pcs | 757,00 |
| K05.100 | YES | OTDR distance scale calibration, SM, at one wavelength | Pcs | 489,00 |
| | | | | |

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| Item No. | Accre- dited | Description | Unit | Sales price [Euro] |
|-------------|-----------------|---|------|-----------------------|
| K05.101 | YES | OTDR distance scale calibration, SM, per subsequent measurement or wavelength | Pcs | 185,00 |
| K05.201 | NO | Relative intensity noise (RIN), 1st meas., per source | Pcs | 508,00 |
| K05.099 | Contact DFM | Power meter/detector calibration visible light acc. to quotation | Pcs | |
| K05.999 | Contact DFM | Radiometric calibration according to quotation | Pcs | |
| Calibration | of mass | | | |
| K06.001 | YES | Calibration of weights, per pcs., when 3 weights or more | Pcs | 133,00 |
| K06.003 | YES | Calibration of 1 or 2 weights | Pcs | 361,00 |
| K06.999 | Contact DFM | Calibration of weights according to quotation | Pcs | |
| Calibration | and measureme | ent on the micro- and nanometre scale | | |
| K07.001 | YES | AFM calibration of two-dimensional grating, first grating | Pcs | 690,00 |
| K07.002 | YES | Subsequent gratings, each | Pcs | 532,00 |
| K07.003 | YES | Calibration of step height with AFM | Pcs | 659,00 |
| K07.101 | NO | Roughness measurement, image and raw data measuring on one spot, first time image and first time sample | Pcs | 439,00 |
| K07.102 | NO | Roughness measurement, image and raw data, further samples, first image, same order | Pcs | 212,00 |
| K07.103 | NO | Roughness measurement, image raw data. Same sample, further images | Pcs | 147,00 |
| K07.104 | NO | Roughness analysis including report. Measurement on one spot, first image | Pcs | 781,00 |
| K07.105 | NO | Roughness analysis including report, same session, further samples, first image | Pcs | 342,00 |
| K07.106 | NO | Roughness analysis including report. Same sample, further images | Pcs | 228,00 |
| K07.107 | NO | Long range scan 500 µm x 500 µm x 6 µm incl. report | Pcs | 1.554,00 |
| K07.120 | NO | Calibration of optical graticule (dot size normal, 8 dots*) 1 µm - 50 µm, *for a different number of dots, contact DFM for a quotation | Pcs | 1.554,00 |
| K07.140 | NO | Measurement of local surface potential (Kelvin Probe Microscopy) | Pcs | 435,00 |
| K07.141 | NO | Measurement of local surface potential (Kelvin Probe Microscopy), including report | Pcs | 777,00 |
| Calibration | and measureme | ent on the micro- and nanometre scale, surface investigations | | |
| K07.201 | NO | Surface investigations in liquid environment, image and raw data. Measuring on one spot in liquid cell, first image | Pcs | 601,00 |
| K07.202 | NO | Surface investigations in liquid environment, image and raw data. Same session, further samples, first image | Pcs | 293,00 |
| K07.203 | NO | Surface investigations in liquid environment, image and raw data. Same sample, further images | Pcs | 179,00 |
| K07.204 | NO | Surface investigations in liquid environment including report. Measuring on one spot, first image | Pcs | 944,00 |
| | | Surface investigations in liquid environment including report. Same | | 439,00 |

| K07.201 | NO | Surface investigations in liquid environment, image and raw data. Measuring on one spot in liquid cell, first image | Pcs | 601,00 |
|---------|----|--|-----|--------|
| K07.202 | NO | Surface investigations in liquid environment, image and raw data. Same session, further samples, first image | Pcs | 293,00 |
| K07.203 | NO | Surface investigations in liquid environment, image and raw data. Same sample, further images | Pcs | 179,00 |
| K07.204 | NO | Surface investigations in liquid environment including report. Measuring on one spot, first image | Pcs | 944,00 |
| K07.205 | NO | Surface investigations in liquid environment including report. Same session, further samples, first image | Pcs | 439,00 |
| K07.206 | NO | Surface investigations in liquid environment including report. Same sample, further images | Pcs | 260,00 |
| K07.210 | NO | AFM measurement of adhesion, acc. to quotation | | |
| K07.211 | NO | AFM measurement of structural surface stability, acc. to quotation | | |
| | | | | |

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| ltem No. | Accre- dited | Description | Unit | Sales price [Euro] |
|----------|-----------------|--|------|-----------------------|
| K07.301 | NO | Use of AFM facility (for experienced users), excl. consultancy, first day | Pcs | 342,00 |
| K07.302 | NO | Use of AFM facility (for experienced users), excl. consultancy, following days in succession, per day | Pcs | 179,00 |
| K07.303 | NO | Surface investigations by/with a DFM scientist (incl. reporting), time registered pr. started 1/2 hour. Price pr. hour | Hour | 225,00 |
| K07.999 | Contact DFM | Surface measurement, according to quotation | Pcs | |

Calibration and measurement on the micro- and nanometre scale, interference- and confocal microscopy

| K07.304 | Contact DFM | Confocal and interference microscope measurements, according to quotation | Pcs | |
|---------|-------------|---|-----|--------|
| K07.305 | NO | Geometrical characterization of silicon line gratings (line width (CD), height and sidewall angle), according to quotation | Pcs | |
| K07.306 | NO | Roughness measurements with confocal/interference microscope, first site, measurement and sample | Pcs | 329,00 |
| K07.307 | NO | Roughness measurements with confocal/interference-microscope, following site or measurement, same session | Pcs | 135,00 |
| K07.308 | YES | Calibration of step height with confocal/interference microscope, first site, measurement and sample | Pcs | 520,00 |
| K07.309 | YES | Calibration of step height with confocal/interference microscope, following site or measurement, same session | Pcs | 442,00 |
| K07.310 | YES | Lateral calibration of two-dimensional grating with confocal/interference microscope, first site, measurement and sample | Pcs | 544,00 |
| K07.311 | YES | Lateral calibration of two-dimensional grating with confocal/interference microscope, following site or measurement, same session | Pcs | 420,00 |

Calibration and measurement on the micro- and nanometre scale, other services

| K07.399 | NA | Special tips for AFM, according to quotation | Pcs | |
|---------|-------------|--|-----|--------|
| K07.405 | NO | Ellipsometric measurement of film thickness/optical constants (single point) | Pcs | 388,00 |
| K07.406 | NO | Ellipsometric measurement of film thickness/optical constants (Multiple points) according to quotation | Pcs | |
| K07.501 | NO | Replication of surfaces using polymer imprints, according to quotation | Pcs | |
| K07.600 | NO | Profilometric measurement, height, according to quotation | Pcs | |
| K07.601 | NO | Profilometric measurement, form/lateral, according to quotation | Pcs | |
| K07.602 | NO | Profilometric measurement, roughness, according to quotation | Pcs | |
| K07.700 | NO | Interferometric calibration of films and sheets, acc. to quotation | Pcs | |
| K07.998 | Contact DFM | Measurement of Young's Modulus, according to quotation | Pcs | |
| K07.999 | Contact DFM | Surface measurement, according to quotation | Pcs | |

Acoustic calibration services

| K08.001 | YES | Microphone, pressure, reciprocity, LS1 | Pcs | 1.471,00 |
|---------|-----|--|-----|----------|
| K08.002 | YES | Microphone, pressure, reciprocity, LS2 | Pcs | 1.471,00 |
| K08.003 | YES | Microphone, free-field, reciprocity, LS1 | Pcs | 2.475,00 |
| K08.004 | YES | Microphone, free-field, reciprocity, LS2 | Pcs | 2.946,00 |
| K08.005 | YES | Microphone, free-field comparison (LS1, LS2, WS1 or WS2) | Pcs | 703,00 |

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| Item No. | Accre- dited | Description | Unit | Sales price [Euro] |
|----------|-----------------|---|------|-----------------------|
| K08.006 | YES | Microphone, free-field comparison (as K08.005, basic service) | Pcs | 391,00 |
| K08.007 | YES | As K08.006, following microphone, same order/session | Pcs | 326,00 |
| K08.008 | YES | Microphone, pressure comparison (LS1, LS2, WS1 or WS2) | Pcs | 703,00 |
| K08.009 | YES | Microphone, pressure comparison (as K08.008, basic service) | Pcs | 458,00 |
| K08.010 | YES | Microphone, HF-calibration, free-field reciprocity WS3 | Pcs | 2.946,00 |
| K08.011 | YES | Microphone, HF-calibration, free-field comparison WS3 | Pcs | 821,00 |
| K08.012 | YES | Microphone, HF-calibration (as K08.011, basic service) | Pcs | 563,00 |
| K08.201 | YES | Actuator response (LS1, LS2, WS1 or WS2) | Pcs | 259,00 |
| K08.202 | YES | Actuator response, (LS1, LS2, WS1 or WS2), basic service | Pcs | 163,00 |
| K08.203 | YES | Actuator response, HF to 100 kHz | Pcs | 359,00 |
| K08.204 | YES | Actuator response, HF to 100 kHz, basic service | Pcs | 254,00 |
| K08.205 | YES | Pistonphone calibration | Pcs | 413,00 |
| K08.206 | YES | Calibration of sound calibrator (one frequency) | Pcs | 372,00 |
| K08.207 | YES | Calibration of sound calibrator (one frequency), basic service | Pcs | 281,00 |
| K08.301 | YES | Ear simulator, calibration re. IEC 60318-1, IEC 60318-4 | Pcs | 746,00 |
| K08.101 | NO | Additional testing, microphone, noise floor, acc. to quotation | Pcs | |
| K08.102 | NO | Additional testing, microphone, membrane inspection, acc. to quotation | Pcs | |
| K08.103 | NO | Additional testing, microphone, temperature coeff., acc. to quotation | Pcs | |
| K08.104 | NO | Additional testing, microphone, static pressure coeff., acc. to quotation | Pcs | |
| K08.105 | NO | Additional testing, microphone, DC leakage test, acc. to quotation | Pcs | |
| K08.999 | Contact DFM | Acoustic measurement / calibration according to quotation | Pcs | |

Calibration of particle counters

| K09.001 | YES | Calibration of counting efficiency (CE), one particle counter, at one particle size | Pcs | 391,00 |
|---------|-------------|---|-----|--------|
| K09.002 | YES | Additional particle sizes in the calibration of CE, price per additional size, same measurement session | Pcs | 244,00 |
| K09.003 | NO | Additional ISO 21501-4 tests according to data sheet, price per counter | Pcs | 129,00 |
| K09.006 | NO | Additional Size Setting and Size Resolution, per new size | Pcs | 209,00 |
| K09.007 | NO | Additional Size Setting and Size Resolution, per CE size | Pcs | 104,00 |
| K09.101 | YES | Reference particles (100 nm - 5 μm diameter) calibrated by AFM; DFM selects and delivers particles; Price is excl. particles | Pcs | 700,00 |
| K09.102 | YES | Reference particles (100 nm - 5 µm diameter) calibrated by AFM (customer provides particles) | Pcs | 583,00 |
| K09.999 | Contact DFM | Particle measurements according to quotation | Pcs | |

Roughness and coordinate metrology

| K11.001 | YES | Calibration, roughness meter; Parameter calibration (1st ampl. step) | Pcs | 705,00 |
|---------|-----|--|-----|--------|
| K11.002 | YES | Calibration, roughness meter; Amplification (1st ampl. step) | Pcs | 626,00 |
| K11.003 | YES | Calibration, roughness meter; Total calibration (1st ampl. step) | Pcs | 783,00 |
| K11.004 | YES | Calibration, roughness meter; Each subsequent ampl. step | Pcs | 234,00 |
| K11.005 | YES | Adjust. after K11.001, and subsequent param. cal. (one step) | Pcs | 421,00 |



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| Item No. | Accre- dited | Description | Unit | Sales price [Euro] |
|----------|-----------------|--|------|-----------------------|
| K11.100 | YES | Calibration, roughness artefact; ISO Type C | Pcs | 548,00 |
| K11.101 | YES | Calibration, roughness artefact; ISO A1 (wide grooves, flat bottoms), 2 grooves | Pcs | 548,00 |
| K11.102 | YES | Calibration, roughness artefact; ISO A2 (wide grooves, rounded bottoms), 6 grooves | Pcs | 1.800,00 |
| K11.103 | YES | Calibration, roughness artefact; ISO B2 (grooves with single shape) | Pcs | 548,00 |
| K11.108 | YES | Calibration, roughness artefact; ISO D (irregular profile, one direction) | Pcs | 705,00 |
| K11.201 | YES | Calibration, hole-plate artefacts, test report, one position | Pcs | 569,00 |
| K11.202 | YES | Calibration, hole-plate artefacts, acc. to DKD guidelines | Pcs | 1.700,00 |
| K11.999 | Contact DFM | Tactile roughness test, according to quotation | Pcs | |

Certified reference solutions for electrolytic conductivity

| R03.001 | YES | Reference solution, 0.5 litre KCI in H_2O , 0.01 S/m | Pcs | 482,00 |
|---------|-------------|--|-----|--------|
| R03.002 | YES | Reference solution, 0.5 litre KCI in H ₂ O, 0.1 S/m | Pcs | 482,00 |
| R03.003 | YES | Reference solution, 0.5 litre KCI in H ₂ O, 1,0 S/m | Pcs | 482,00 |
| R03.004 | YES | Reference solution, 0.5 litre KCl in H ₂ O, 10 S/m | Pcs | 482,00 |
| R03.999 | Contact DFM | Reference solution, batch made on demand, acc. to quotation | Pcs | |

pH reference solutions

| R03.101 | YES | Primary pH buffer 'Phthalate' (pH = 4.005) | Pcs | 5.042,00 |
|---------|-----|---|-----|----------|
| R03.102 | YES | Primary pH buffer '1:1 phosphate' (pH = 6.865) | Pcs | 5.042,00 |
| R03.103 | YES | Primary pH buffer '1:3.5 phosphate (pH = 7.413) | Pcs | 5.042,00 |
| R03.104 | YES | Primary pH buffer 'Borate' (pH = 9.180) | Pcs | 5.042,00 |
| R03.105 | YES | Primary pH buffer 'Carbonate' (pH = 10.012) | Pcs | 5.042,00 |
| R03.106 | YES | Secondary pH buffer '1:4 phosphate' (pH = 7.38) | Pcs | 5.042,00 |

Stabilized lasers

| P01.001 | Stabiλaser 1542, acetylene-stabilized laser | STK | 42.800,00 |
|---------|---|-----|-----------|
| P01.002 | Stabiλaser 771 acetylene-stabilized laser | STK | 60.290,00 |

DFM Software

| S01.003 | NA | DFM Calibration Datasheet 2000 for MS Excel, acc. to quotation | Pcs |
|---------|----|--|-----|
| S08.002 | NA | Acoustics software MP.EXE, version 4, acc. to quotation | Pcs |
| S08.003 | NA | Upgrade to MP.EXE, version 4, acc. to quotation | Pcs |

Consultancy services

| YDE1 | NA | Consultancy, Senior Scientist (hourly rate) | Hour | 201,00 |
|------|----|---|------|--------|
| YDE2 | NA | Consultancy, Scientist (hourly rate) | Hour | 167,00 |
| YDE3 | NA | Consultancy, Technician (hourly rate) | Hour | 134,00 |



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| Item No. | Accre- | Description |
|----------|--------|-------------|
| | dited | |

Unit Sales price [Euro]

The pricing is valid from the date above until new prices are issued. Updated and most recent pricing is available at https://dfm.dk/. Services not mentioned in the above list of standard services are invoiced at hourly rates per agreement. All pricing is EXW DFM, Hørsholm (Incoterms 2010), and is excl. VAT.